ANNUAL INDEX VOL. 26 1992

COURSES, ARTICLES, BUYERS GUIDES

KEY

Number in parentheses is issue number; other number is page number.
(151)100 = Issue 151, Page 100

Issue 151 = February, 1992
Issue 152 = April, 1992
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Issue 154 = September, 1992
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{8} Computers
{9} Moisture / Humidity
{10} General Instrumentation

PROFESSIONAL COURSES

C-Language Programming, Part 3 — Control Structures, Clarence De Silva, Ph.D., PE and Lalith Gamage, MS (151)85 *8*

C-Language Programming, Part 4 — Pointers and Other Operators, Clarence De Silva, Ph.D., PE and Lalith Gamage, MS (152)70 *8*

C-Language Programming, Part 5 — Arrays, Clarence De Silva, Ph.D., PE and Lalith Gamage, MS (153)78 *8*

C-Language Programming, Part 6 — Functions, Clarence De Silva, Ph.D., PE and Lalith Gamage, MS (154)120 *8*

C-Language Programming, Part 7 — Constructed Data Types, Clarence De Silva, Ph.D., PE and Lalith Gamage, MS (155)80 *8*

C-Language Programming, Part 8 — Storage Classes, Clarence De Silva, Ph.D., PE and Lalith Gamage, MS (156)72 *8*

DOS, Part 4 — Directory PATH and TREE, Mike Clark, New Age Electronics (151)92 *8*

DOS, Part 5 — File Names and Types, Mike Clark, New Age Electronics (152)86 *8*

DOS, Part 6 — Getting Started with COMMAND.COM, AUTOEXEC.BAT and CONFIG.SYS, Mike Clark, New Age Electronics (153)90 *8*

DOS, Part 7 — Configure the System with CONFIG.SYS, Mike Clark, New Age Electronics (154)117 *8*

DOS, Part 8 — Batch Files, Mike Clark, New Age Electronics (155)78 *8*

DOS, Part 9 — Command Switches, Mike Clark, New Age Electronics (156)66 *8*

Low-Level Measurements, Part 1 — Introduction, Charles Cimino, Keithley Instruments (154)136 *2*

Low-Level Measurements, Part 2 — Instrument Errors, Paul Moore, Keithley Instruments (155)69 *2*

Low-Level Measurements, Part 3 — Non-Instrument Related Errors, Greg Sobolewski, Keithley Instruments (156)61 *2*

Photoelectric Sensing, Part 3, Fred W. Poppe, Allen-Bradley (151)95 *1*

Photoelectric Sensing, Part 4, Fred W. Poppe, Allen-Bradley (152)82 *1*

Transient Recording Techniques, Part 1 — Registration and Analysis of Transient Events, John Hueckel, Pacific Instruments and Cees De Vries, Bakker Electronics (151)98 *6*

Transient Recording Techniques, Part 2 — From Analog to Digital, John Hueckel, Pacific Instruments and Cees De Vries, Bakker Electronics (152)76 *6*

Transient Recording Techniques, Part 3 — Storage of Digitized Data, John Hueckel, Pacific Instruments and Cees De Vries, Bakker Electronics (153)84 *6*

Transient Recording Techniques, Part 4 — Problem Solving Measurement Techniques, John Hueckel, Pacific Instruments and Cees De Vries, Bakker Electronics (154)130 *6*

ARTICLES

ASIC Enhanced Pressure Sensors, Richard Grove, Keller PSI (154)139 *4*

Balanced-Beam Manometry, Gene Glassey, Fluid Data Systems (153)113 *4*

Calibration Near Reactors, Harold Walker, Florida Power Corp. and Nick Wilks, Druck Inc. (152)88 *4*

CEM — Continuous Emissions Monitoring, Richard Weaver, Chessell Corp. (153)94 *6*

CMM — Coordinate Measuring Machine, Louis Simon, Simco Industries (151)114 *1*

Conductive-Plastic Potentiometers, Ernst Gass and Ernst Holder, Novotechnik (151)116 *2*

Continuous Thermocouple Cable With Smart Controller, Brian Tingey, Pacific Scientific (155)102 *7*

Data Recording, Edwin Kayes, Penny + Giles Data Systems (153)102 *6*

DDC — Distributed Digital Control, Frank C. Pizzurro, Mobay Corporation (152)102 *5*

Expert Systems — Achieve Quality and Competitive Advantage, Joan B. Stoddard, Ph.D., Stoddard Productivity Systems (155)105 *5*

Fiber-Optic Resonator Pressure Transducers, Jerome M. Paros, Paroscientific (154)144 *4*

Flat Panels Challenge CRTs and LCDs, Jonathan Gilbert, Planar Systems (155)87 *8*

Flow Velocity Profiles, Thomas J. Scarpa, Edinboro Technologies (154)166 *3*

Instruments for Industrial and Research Applications, Neil Pope, Techne (154)149 *7*

Low-Power DC-Solenoid Valves, Donald Hoerr, Herion (154)142 *5*

Magnetostrictive Tank Gauging, Wade D. Peterson, MTS Systems Corp. (153)108 *3*

MAN — Metropolitan Area Network, Rouzbeh Yassini, Applitek Inc. (151)104 *8*

Manifold Pressure, Paul E. Allen, Logic Devices (151)134 *4*

Measurements & the Bureaucracy, Part 2, Milton H. Aronson (153)115 *10*

Meter, Laser Interferometers and Interferential Measuring Systems, Dr. Walter Miller, Heidenhain (156)100 *1*

Micromachined & Integrated Silicon Sensors, Randy Frank, Motorola SPS (155)92 *4*

Open-Architecture Process Control, William H. Moss, Computer Products Process Automation (155)98 *5*

Optical Sensors Automate Instrument Timing, Vernon Mathews, Optical Solutions (154)172 *1*

PC and Operator Interface for the Hazardous or Dirty Environment, Dave Reynolds, Azonix (152)90 *5*

PC-Based Data Acquisition, Jack Zettler, Tekonex Associates and Eric Sonnichsen, Test Devices, Inc. (152)96 *6*

Plastic Control Valves, Bill Smith, Collins Instruments (152)100 *5*

Platinum RTD Lithography, Haubold O. vom Berg, JUMO Process Control (156)80 *7*

Portable Dew-Point Generator, K.L. Petersen, Ph.D. and G.L. Biggs, EE, Li-Cor (151)106 *9*

QAPLUS/fe™ Review, Mike Clark, New Age Electronics (152)94 *8*

Recorder Relays, Bruce Zavodny, Johnson Yokogawa (151)110 *6*

Regulators for Flow Control, John Cummings, W.A. Kates (151)102 *3*

Relative Humidity Measurement with an Analog Transmitter, Gerald Schultz, PhysChem Scientific (156)96 *9*

Rotameter Correlation, Roger Gilmont (151)124 *3*

Science Fraud?, Milton H. Aronson (153)117 *10*

Smart Transmitter for Differential-Pressure Measurement, Ralf Jäger, Endress & Hauser (154)157 *4*

Temperature Calibration Chamber, Brett Husselbaugh, TOBEK Computer Systems (154)160 *7*

UV/VIS Spectrometer, Yoav Barshad, Ph.D., NovaChem (153)99 *2*

ANNUAL INDEX VOL. 26 1992

COURSES, ARTICLES, BUYERS GUIDES

KEY

Number in parentheses is issue number; other number is page number.
(151)100 = Issue 151, Page 100

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{9} Moisture / Humidity
{10} General Instrumentation

PROFESSIONAL COURSES

C-Language Programming, Part 3 — Control Structures, Clarence De Silva, Ph.D., PE and Lalith Gamage, MS (151)85 *8*

C-Language Programming, Part 4 — Pointers and Other Operators, Clarence De Silva, Ph.D., PE and Lalith Gamage, MS (152)70 *8*

C-Language Programming, Part 5 — Arrays, Clarence De Silva, Ph.D., PE and Lalith Gamage, MS (153)78 *8*

C-Language Programming, Part 6 — Functions, Clarence De Silva, Ph.D., PE and Lalith Gamage, MS (154)120 *8*

C-Language Programming, Part 7 — Constructed Data Types, Clarence De Silva, Ph.D., PE and Lalith Gamage, MS (155)80 *8*

C-Language Programming, Part 8 — Storage Classes, Clarence De Silva, Ph.D., PE and Lalith Gamage, MS (156)72 *8*

DOS, Part 4 — Directory PATH and TREE, Mike Clark, New Age Electronics (151)92 *8*

DOS, Part 5 — File Names and Types, Mike Clark, New Age Electronics (152)86 *8*

DOS, Part 6 — Getting Started with COMMAND.COM, AUTOEXEC.BAT and CONFIG.SYS, Mike Clark, New Age Electronics (153)90 *8*

DOS, Part 7 — Configure the System with CONFIG.SYS, Mike Clark, New Age Electronics (154)117 *8*

DOS, Part 8 — Batch Files, Mike Clark, New Age Electronics (155)78 *8*

DOS, Part 9 — Command Switches, Mike Clark, New Age Electronics (156)66 *8*

Low-Level Measurements, Part 1 — Introduction, Charles Cimino, Keithley Instruments (154)136 *2*

Low-Level Measurements, Part 2 — Instrument Errors, Paul Moore, Keithley Instruments (155)69 *2*

Low-Level Measurements, Part 3 — Non-Instrument Related Errors, Greg Sobolewski, Keithley Instruments (156)61 *2*

Photoelectric Sensing, Part 3, Fred W. Poppe, Allen-Bradley (151)95 *1*

Photoelectric Sensing, Part 4, Fred W. Poppe, Allen-Bradley (152)82 *1*

Transient Recording Techniques, Part 1 — Registration and Analysis of Transient Events, John Hueckel, Pacific Instruments and Cees De Vries, Bakker Electronics (151)98 *6*

Transient Recording Techniques, Part 2 — From Analog to Digital, John Hueckel, Pacific Instruments and Cees De Vries, Bakker Electronics (152)76 *6*

Transient Recording Techniques, Part 3 — Storage of Digitized Data, John Hueckel, Pacific Instruments and Cees De Vries, Bakker Electronics (153)84 *6*

Transient Recording Techniques, Part 4 — Problem Solving Measurement Techniques, John Hueckel, Pacific Instruments and Cees De Vries, Bakker Electronics (154)130 *6*

ARTICLES

ASIC Enhanced Pressure Sensors, Richard Grove, Keller PSI (154)139 *4*

Balanced-Beam Manometry, Gene Glassey, Fluid Data Systems (153)113 *4*

Calibration Near Reactors, Harold Walker, Florida Power Corp. and Nick Wilks, Druck Inc. (152)88 *4*

CEM — Continuous Emissions Monitoring, Richard Weaver, Chessell Corp. (153)94 *6*

CMM — Coordinate Measuring Machine, Louis Simon, Simco Industries (151)114 *1*

Conductive-Plastic Potentiometers, Ernst Gass and Ernst Holder, Novotechnik (151)116 *2*

Continuous Thermocouple Cable With Smart Controller, Brian Tingey, Pacific Scientific (155)102 *7*

Data Recording, Edwin Kayes, Penny + Giles Data Systems (153)102 *6*

DDC — Distributed Digital Control, Frank C. Pizzurro, Mobay Corporation (152)102 *5*

Expert Systems — Achieve Quality and Competitive Advantage, Joan B. Stoddard, Ph.D., Stoddard Productivity Systems (155)105 *5*

Fiber-Optic Resonator Pressure Transducers, Jerome M. Paros, Paroscientific (154)144 *4*

Flat Panels Challenge CRTs and LCDs, Jonathan Gilbert, Planar Systems (155)87 *8*

Flow Velocity Profiles, Thomas J. Scarpa, Edinboro Technologies (154)166 *3*

Instruments for Industrial and Research Applications, Neil Pope, Techne (154)149 *7*

Low-Power DC-Solenoid Valves, Donald Hoerr, Herion (154)142 *5*

Magnetostrictive Tank Gauging, Wade D. Peterson, MTS Systems Corp. (153)108 *3*

MAN — Metropolitan Area Network, Rouzbeh Yassini, Applitek Inc. (151)104 *8*

Manifold Pressure, Paul E. Allen, Logic Devices (151)134 *4*

Measurements & the Bureaucracy, Part 2, Milton H. Aronson (153)115 *10*

Meter, Laser Interferometers and Interferential Measuring Systems, Dr. Walter Miller, Heidenhain (156)100 *1*

Micromachined & Integrated Silicon Sensors, Randy Frank, Motorola SPS (155)92 *4*

Open-Architecture Process Control, William H. Moss, Computer Products Process Automation (155)98 *5*

Optical Sensors Automate Instrument Timing, Vernon Mathews, Optical Solutions (154)172 *1*

PC and Operator Interface for the Hazardous or Dirty Environment, Dave Reynolds, Azonix (152)90 *5*

PC-Based Data Acquisition, Jack Zettler, Tekonex Associates and Eric Sonnichsen, Test Devices, Inc. (152)96 *6*

Plastic Control Valves, Bill Smith, Collins Instruments (152)100 *5*

Platinum RTD Lithography, Haubold O. vom Berg, JUMO Process Control (156)80 *7*

Portable Dew-Point Generator, K.L. Petersen, Ph.D. and G.L. Biggs, EE, Li-Cor (151)106 *9*

QAPLUS/fe™ Review, Mike Clark, New Age Electronics (152)94 *8*

Recorder Relays, Bruce Zavodny, Johnson Yokogawa (151)110 *6*

Regulators for Flow Control, John Cummings, W.A. Kates (151)102 *3*

Relative Humidity Measurement with an Analog Transmitter, Gerald Schultz, PhysChem Scientific (156)96 *9*

Rotameter Correlation, Roger Gilmont (151)124 *3*

Science Fraud?, Milton H. Aronson (153)117 *10*

Smart Transmitter for Differential-Pressure Measurement, Ralf Jäger, Endress & Hauser (154)157 *4*

Temperature Calibration Chamber, Brett Husselbaugh, TOBEK Computer Systems (154)160 *7*

UV/VIS Spectrometer, Yoav Barshad, Ph.D., NovaChem (153)99 *2*

Vibration Monitoring With Piezoelectric Sensors, Richard Barrett, Fred Wilcoxon and Fred Schloss, Wilcoxon Research (156)86 *1*

Which Thermocouple is Best? The Commercial Realities in the 90s, Allan Paine, Leeds & Northrup (154)152 *7*

Why, On Earth, Would Environmental Scientists Cheat?, Gene Glassey, Fluid Data Systems (153)120 *10*

OPINIONS

Almgren, Raymond, National Instruments, Windows for Data Acquisition and Control (154)234 *5*

Anderson, Lynn, Western Graphtec, Pen Recorders Come Full-Circle (156)158 *6*

Baumoel, Joseph, Controlotron, Why Not Consider Using An Ultrasonic Flowmeter? (155)189 *3*

Beck, Tom, and Dr. Jacques Mettes, MEECO Inc., Manufacturers Today Require PPM Moisture Detection, Rapid Response and Reliability (151)182 *9*

Binsfeld, Mike, Binsfeld Engineering, Inc., Measuring Torque on Rotating Shafts: Telemetry is a Better Way (151)217 *4*

Birdsey, Robert A., Dresser Industries, Now — Electronic Pressure Switches at Affordable Prices (154)223 *4*

Bugher, Gary, Endress + Hauser, Mass Flowmeters Measure Multiple Process Variables (154)215 *3*

Clarridge, Ronald, Altek Industries, Digital Potentiometers Simplify and Improve Calibration (154)259 *2*

Mettes, Dr. Jacques, and Tom Beck, MEECO Inc., Manufacturers Today Require PPM Moisture Detection, Rapid Response and Reliability (151)182 *9*

Owens, Bill, Johnson Yokogawa, Reports of a Chart Paper's Demise Are a Bit Premature! (156)155 *6*

Page, Frank, Eaton Pressure Sensors Div., The Future of Portable Calibration, (156)132 *4*

Pohl, Ernie, Science/Electronics, Temperature Calibration Baths — State-of-the-Art (154)265 *7*

Robinson, Dr. James, TEC, Reliable Vibration Measurement for Low Speed Machinery Now Can Be Obtained Down to 6 RPM (152)109 *1*

Scelzo, Michael J., Panametrics, Inc., The Trend is Toward Processing and Measurement at "Ultralow" Moisture Levels (151)189 *9*

Shirley, Paul, Massa Products, Technological Developments for Short-Range Level Measurement (152)131 *3*

Smith, Ernest, Johnson Yokogawa Corp., The New Frontier — The Human Factor (152)150 *5*

Warren, Cliff, Raytek, Inc., IR Non-Contact Temperature Sensors Expand Up and Down the Line (151)206 *7*

AUTHORS

Allen, Paul E., Logic Devices, Manifold Pressure (151)134

Aronson, Milton H., Measurements and the Bureaucracy, Part 2 (153)115

Aronson, Milton H., Science Fraud? (153)117

Barrett, Richard, Fred Wilcoxon and Fred Schloss, Wilcoxon Research, Vibration Monitoring With Piezoelectric Sensors (156)86

Barshad, Yoav, Ph.D., NovaChem, UV/VIS Spectrometer (153)99

Biggs, G.L. and K.L. Petersen, Ph.D., Li-Cor, Portable Dew-Point Generator (151)106

Cimino, Charles, Keithley Instruments, Low-Level Measurements, Part 1 — Introduction (154)136

Clark, Mike, DOS, Part 4 — Directory PATH and TREE (151)92

Clark, Mike, New Age Electronics, DOS, Part 5 — File Names and Types (152)86

Clark, Mike, New Age Electronics, DOS, Part 6 — Getting Started with COMMAND.COM, AUTOEXEC.BAT and CONFIG.SYS (153)90

Clark, Mike, New Age Electronics, DOS, Part 7 — Configure the System with CONFIG.SYS (154)117

Clark, Mike, New Age Electronics, DOS, Part 8 — Batch Files (155)78

Clark, Mike, New Age Electronics, DOS, Part 9 — Command Switches (156)66

Cummings, John, W.A. Kates, Regulators for Flow Control (151)102

De Silva, Clarence, Ph.D., PE and Lalith Gamage, MS, C-Language Programming, Part 3 — Control Structures (151)85

De Silva, Clarence, Ph.D., PE and Lalith Gamage, MS, C-Language Programming, Part 4 — Pointers and Other Operators (152)70

De Silva, Clarence, Ph.D., PE and Lalith Gamage, MS, C-Language Programming, Part 5 — Arrays (153)78

De Silva, Clarence, Ph.D., PE and Lalith Gamage, MS, C-Language Programming, Part 6 — Functions (154)120

De Silva, Clarence, Ph.D., PE and Lalith Gamage, MS, C-Language Programming, Part 7 — Constructed Data Types (155)80

De Silva, Clarence, Ph.D., PE and Lalith Gamage, MS, C-Language Programming, Part 8 — Storage Classes (156)72

De Vries, Cees, Bakker Electronics and John Hueckel, Pacific Instruments, Transient Recording Techniques, Part 1 — Registration and Analysis of Transient Events (151)98

De Vries, Cees, Bakker Electronics and John Hueckel, Pacific Instruments, Transient Recording Techniques, Part 2 — From Analog to Digital (152)76

De Vries, Cees, Bakker Electronics and John Hueckel, Pacific Instruments, Transient Recording Techniques, Part 3 — Storage of Digitized Data (153)84

De Vries, Cees, Bakker Electronics and John Hueckel, Pacific Instruments, Transient Recording Techniques, Part 4 — Problem Solving Measurement Techniques (154)130

Frank, Randy, Motorola SPS, Micromachined & Integrated Silicon Sensors (155)92

Gamage, Lalith, MS and Clarence De Silva, Ph.D., PE, C-Language Programming, Part 3 — Control Structures (151)85

Gamage, Lalith, MS and Clarence De Silva, Ph.D., PE, C-Language Programming, Part 4 — Pointers and Other Operators (152)70

Gamage, Lalith, MS and Clarence De Silva, Ph.D., PE, C-Language Programming, Part 5 — Arrays (153)78

Gamage, Lalith, MS and Clarence De Silva, Ph.D., PE, C-Language Programming, Part 6 — Functions (154)120

Gamage, Lalith, MS and Clarence De Silva, Ph.D., PE, C-Language Programming, Part 7 — Constructed Data Types (155)80

Gamage, Lalith, MS and Clarence De Silva, Ph.D., PE, C-Language Programming, Part 8 — Storage Classes (156)72

Gass, Ernst and Ernst Holder, Novotechnik, Conductive-Plastic Potentiometers (151)116

Gilbert, Jonathan, Planar Systems, Flat Panels Challenge CRTs and LCDs (155)87

Gilmont, Roger, Rotameter Correlation (151)124

Glassey, Gene, Fluid Data Systems, Balanced-Beam Manometry (153)113

Glassey, Gene, Fluid Data Systems, Why, On Earth, Would Environmental Scientists Cheat? (153)120

Grove, Richard, Keller PSI, ASIC Enhanced Pressure Sensors (154)139

Hoerr, Donald, Herion, Low-Power DC-Solenoid Valves (154)142

Holder, Ernst and Ernst Gass, Novotechnik, Conductive-Plastic Potentiometers (151)116

Hueckel, John, Pacific Instruments and Cees De Vries, Bakker Electronics, Transient Recording Techniques, Part 1 — Registration and Analysis of Transient Events (151)98

Hueckel, John, Pacific Instruments and Cees De Vries, Bakker Electronics, Transient Recording Techniques, Part 2 — From Analog to Digital (152)76

Hueckel, John, Pacific Instruments and Cees De Vries, Bakker Electronics, Transient Recording Techniques, Part 3 — Storage of Digitized Data (153)84

Hueckel, John, Pacific Instruments and Cees De Vries, Bakker Electronics, Transient Recording Techniques, Part 4 — Problem Solving Measurement Techniques (154)130

Husselbaugh, Brett, TOBEK Computer Systems, Temperature Calibration Chamber (154)160

Jäger, Ralf, Endress & Hauser, Smart Transmitter for Differential-Pressure Measurement (154)157

Kayes, Edwin, Penny + Giles Data Systems, Data Recording (153)102

Mathews, Vernon, Optical Solutions, Optical Sensors Automate Instrument Timing (154)172

Miller, Dr. Walter, Heidenhain, Meter, Laser Interferometers and Interferential Measuring Systems (156)100

Moore, Paul, Keithley Instruments, Low-Level Measurements, Part 2 — Instrument Errors (155)69

Moss, William H., Computer Products Process Automation, Open-Architecture Process Control (155)98

Paine, Allen, Leeds & Northrup, Which Thermocouple is Best? The Commercial Realities in the 90s (154)152

Paros, Jerome M., Paroscientific, Fiber-Optic Resonator Pressure Transducers (154)144

Petersen, K.L., Ph.D., and G.L. Biggs, Li-Cor, Portable Dew-Point Generator (151)106

Peterson, Wade D., MTS Systems Corp., Magnetostrictive Tank Gauging (153)108

Pizzurro, Frank C., Mobay Corporation, DDC — Distributed Digital Control (152)102

Pope, Neil, Techne, Instruments for Industrial and Research Applications (154)149

Poppe, Fred W., Allen-Bradley, Photoelectric Sensing, Part 3 (151)95

Poppe, Fred W., Allen-Bradley, Photoelectric Sensing, Part 4 (152)82

Reynolds, Dave, Azonix, PC and Operator Interface for the Hazardous or Dirty Environment (152)90

Scarpa, Thomas J., Edinboro Technologies, Flow Velocity Profiles (154)166

Schloss, Fred, Richard Barrett and Fred Wilcoxon, Wilcoxon Research, Vibration Monitoring With Piezoelectric Sensors (156)86

Schultz, Gerald, Phys-Chem Scientific, Relative Humidity Measurement with an Analog Transmitter (156)96

Simon, Louis, Simco Industries, CMM — Coordinate Measuring Machine (151)114

Smith, Bill, Collins Instruments, Plastic Control Valves (152)100

Sobolewski, Greg, Keithley Instruments, Low-Level Measurements, Part 3 — Non-Instrument Related Errors (156)61

Sonnichsen, Eric, Test Devices, Inc. and Jack Zettler, Tekonex Associates, PC-Based Data Acquisition (152)96

Stoddard, Joan B., Ph.D., Stoddard Productivity Systems, Expert Systems — Achieve Quality and Competitive Advantage (155)105

Tingey, Brian, Pacific Scientific, Continuous Thermocouple Cable With Smart Controller (155)102

vom Berg, Haubold O., JUMO Process Control, Platinum RTD Lithography (156)80

Walker, Harold, Florida Power Corp. and Nick Wilks, Druck Inc., Calibration Near Reactors (152)88

Weaver, Richard, Chessell Corp., CEM — Continuous Emissions Monitoring (153)94

Wilcoxon, Fred, Fred Schloss and Richard Barrett, Wilcoxon Research, Vibration Monitoring With Piezoelectric Sensors (156)86

Wilks, Nick, Druck Inc. and Harold Walker, Florida Power Corp., Calibration Near Reactors (152)88

Yassini, Rouzbeh, Applitek Inc., MAN — Metropolitan Area Network (151)104

Zavodny, Bruce, Johnson Yokogawa, Recorder Relays (151)110

Zettler, Jack, Tekonex Associates and Eric Sonnichsen, Test Devices, Inc., PC-Based Data Acquisition (152)96

BUYERS GUIDE

Acceleration / Vibration (156)107

Analog Controllers, Meter Relays (151)137

Analog Test Meters / Panel Meters (151)144

Anemometers (153)124

Annunciators (155)115

Bimetallic Thermometers (155)118

Bourdon Pressure Gauges (156)120

Bridges & Potentiometers (153)129

Capacitive Pressure Transducers (153)133

Control Valves — Butterfly, Ball, Rotary Stem (156)125

Control Valves — Globe/Plug/Pinch/Needle/Gate (151)150

Control Valves — Regulator / Safety / Relief / Check (153)136

Control Valves — Solenoid (154)176

Counters, Frequency, Tachometers (152)105

Data Acquisition Systems (151)153

Deadweight Testers, Pressure Calibrators (156)129

Density / Specific Gravity (155)123

Differential Pressure Flowmeters (154)179

Digital Pressure Transducers (154)188

DPM, DVM, DMM (156)134

DSO (Digital Storage Oscilloscopes) (155)128

Electromagnetic Flowmeters (152)115

Enclosures (151)168

Encoders, Resolvers, Digitizers (154)191

Filled-Systems Thermometers (154)200

Filters (154)206

Flow Switches (153)140

Galvanometer Direct-Writing Recorders (152)120

Gas Detectors & Analyzers (155)133

Integrated Circuit Thermometers (151)171

Level Measurement & Control (152)124

Light Beam Recorders (154)211

Linear Array Recorders (153)145

Lock-in Amplifiers (152)145

LVDT — Linear Variable Differential Transformers (153)148

Magnetic Measurements, Materials, Shielding (153)153

Manometers (155)143

Mass Flowmeters (154)212

Mass/Force Measurement, Load Cells (155)149

Moisture / Humidity Instruments (151)173

Open-Channel Flowmeters (156)147

Operator Interfaces / Workstations (152)147

Piezoelectric Pressure Transducers (155)161

Positive Displacement Flowmeters (155)167

Potentiometric Pressure Transducers (151)193

Potentiometric (Servo) Recorders (156)152

Power Measurement & Analysis (156)160

Pressure Switches (154)221

Programmable Controllers, Industrial Computers (154)228

Proximity Sensors — Capacitive (151)195

Proximity Sensors — Inductive, Magnetic (156)167

Proximity Sensors — Magnetostrictive (154)241

Proximity Sensors — Microwave (156)173

Proximity Sensors — Optical, Photoelectric, Laser (155)172

Proximity Sensors — Pneumatic (152)154

Proximity Sensors — Ultrasonic (153)159

Radiation Thermometers/Pyrometers (151)198

Recorder Charts, Pens, Accessories (151)208

Reluctive & LVDT Pressure Transducers (154)243

Resistance Thermometers, Thermistors (152)156

Rotameters / Variable-Area Flowmeters (154)247

Rupture Discs (155)176

Spectrum Analyzers (153)163

Standards / Simulators / Calibrators (154)254

Strain-Gage and Piezoresistive Pressure Transducers (152)168

Tape Recorders (155)178

Temperature Calibration Baths (154)262

Temperature Sensitive Paints & Crayons (156)174

Terminal Blocks (153)167

Thermocouples & Accessories (153)171

Tilt Sensors (154)266

Timing & Programming Equipment (154)269

Torque Measurements (151)213

Transient Protectors, Power Conditioners (156)177

Transmitters (153)185

Turbine Flowmeters (151)220

Ultrasonic Flowmeters (155)184

Vacuum Equipment (156)185

Venturi Flowmeters & Valves (155)192

Viscometers (153)198

Vortex Flowmeters (153)202

X-Y Recorders (155)194

COURSES, ARTICLES AND OPINIONS — GROUPED ACCORDING TO SUBJECT

DIMENSION / POSITION / VIBRATION

CMM — Coordinate Measuring Machine, Louis Simon, Simco Industries (151)114

Meter, Laser Interferometers and Interferential Measuring Systems, Dr. Walter Miller, Heidenhain (156)100

Optical Sensors Automate Instrument Timing, Vernon Mathews, Optical Solutions (154)172

Photoelectric Sensing, Part 3, Fred W. Poppe, Allen-Bradley (151)95

Photoelectric Sensing, Part 4, Fred W. Poppe, Allen-Bradley (152)82

Reliable Vibration Measurement for Low Speed Machinery Now Can Be Obtained Down to 6 RPM, Dr. James Robinson, TEC (152)109

Vibration Monitoring With Piezoelectric Sensors, Richard Barrett, Fred Wilcoxon and Fred Schloss, Wilcoxon Research (156)86

ELECTRICAL

Conductive-Plastic Potentiometers, Ernst Gass and Ernst Holder, Novotechnik (151)116

Digital Potentiometers Simplify and Improve Calibration, Ronald Clarridge, Altek Industries (154)259

Low-Level Measurements, Part 1 — Introduction, Charles Cimino, Keithley Instruments (154)136

Low-Level Measurements, Part 2 — Instrument Errors, Paul Moore, Keithley Instruments (155)69

Low-Level Measurements, Part 3 — Non-Instrument Related Errors, Greg Sobolewski, Keithley Instruments (156)61

UV/VIS Spectrometer, Yoav Barshad, Ph.D., NovaChem (153)99

HUMIDITY / MOISTURE

Manufacturers Today Require PPM Moisture Detection, Rapid Response and Reliability, Tom Beck and Dr. Jacques Mettes, MEECO Inc. (151)182

Portable Dew-Point Generator, K.L. Petersen, Ph.D. and G.L. Biggs, EE, Li-Cor (151)106

Relative Humidity Measurement with an Analog Transmitter, Gerald Schultz, PhysChem Scientific (156)96

The Trend is Toward Processing and Measurement at "Ultralow" Moisture Levels, Michael J. Scelzo, Panametrics, Inc. (151)189

RECORDERS

CEM — Continuous Emissions Monitoring, Richard Weaver, Chessell Corp. (153)94

Data Recording, Edwin Kayes, Penny + Giles Data Systems (153)102

PC-Based Data Acquisition, Jack Zettler, Tekonex Associates and Eric Sonnichsen, Test Devices, Inc. (152)96

Pen Recorders Come Full-Circle, Lynn Anderson, Western Graphtec (156)158

Recorder Relays, Bruce Zavodny, Johnson Yokogawa (151)110

Reports of a Chart Paper's Demise Are a Bit Premature!, Bill Owens, Johnson Yokogawa (156)155

Transient Recording Techniques, Part 1 — Registration and Analysis of Transient Events, John Hueckel, Pacific Instruments and Cees De Vries, Bakker Electronics (151)98

Transient Recording Techniques, Part 2 — From Analog to Digital, John Hueckel, Pacific Instruments and Cees De Vries, Bakker Electronics (152)76

Transient Recording Techniques, Part 3 — Storage of Digitized Data, John Hueckel, Pacific Instruments and Cees De Vries, Bakker Electronics (153)84

Transient Recording Techniques, Part 4 — Problem Solving Measurement Techniques, John Hueckel, Pacific Instruments and Cees De Vries, Bakker Electronics (154)130

PRESSURE

ASIC Enhanced Pressure Sensors, Richard Grove, Keller PSI (154)139

Balanced-Beam Manometry, Gene Glassey, Fluid Data Systems (153)113

Calibration Near Reactors, Harold Walker, Florida Power Corp. and Nick Wilks, Druck Inc. (152)88

Fiber-Optic Resonator Pressure Transducers, Jerome M. Paros, Paroscientific (154)144

Manifold Pressure, Paul E. Allen, Logic Devices (151)134

Measuring Torque on Rotating Shafts: Telemetry is a Better Way, Mike Binsfeld, Binsfeld Engineering, Inc. (151)217

Micromachined & Integrated Silicon Sensors, Randy Frank, Motorola SPS (155)92

Now — Electronic Pressure Switches at Affordable Prices, Robert A. Birdsey, Dresser Industries (154)223

Smart Transmitter for Differential-Pressure Measurement, Ralf Jäger, Endress & Hauser (154)157

The Future of Portable Calibration, Frank Page, Eaton Pressure Sensors Div. (156)132

COMPUTERS

C-Language Programming, Part 3 — Control Structures, Clarence De Silva, Ph.D., PE and Lalith Gamage, MS (151)85

C-Language Programming, Part 4 — Pointers and Other Operators, Clarence De Silva, Ph.D., PE and Lalith Gamage, MS (152)70

C-Language Programming, Part 5 — Arrays, Clarence De Silva, Ph.D., PE and Lalith Gamage, MS (153)78

C-Language Programming, Part 6 — Functions, Clarence De Silva, Ph.D., PE and Lalith Gamage, MS (154)120

C-Language Programming, Part 7 — Constructed Data Types, Clarence De Silva, Ph.D., PE and Lalith Gamage, MS (155)80

C-Language Programming, Part 8 — Storage Classes, Clarence De Silva, Ph.D., PE and Lalith Gamage, MS (156)72

DOS, Part 4 — Directory PATH and TREE, Mike Clark, New Age Electronics (151)92

DOS, Part 5 — File Names and Types, Mike Clark, New Age Electronics (152)86

DOS, Part 6 — Getting Started with COMMAND.COM, AUTOEXEC.BAT and CONFIG.SYS, Mike Clark, New Age Electronics (153)90

DOS, Part 7 — Configure the System with CONFIG.SYS, Mike Clark, New Age Electronics (154)117

DOS, Part 8 — Batch Files, Mike Clark, New Age Electronics (155)78

DOS, Part 9 — Command Switches, Mike Clark, New Age Electronics (156)66

Flat Panels Challenge CRTs and LCDs, Jonathan Gilbert, Planar Systems (155)87

MAN — Metropolitan Area Network, Rouzbeh Yassini, Applitek Inc. (151)104

QAPLUS/fe™ Review, Mike Clark, New Age Electronics (152)94

TEMPERATURE

Continuous Thermocouple Cable With Smart Controller, Brian Tingey, Pacific Scientific (155)102

Instruments for Industrial and Research Applications, Neil Pope, Techne (154)149

IR Non-Contact Temperature Sensors Expand Up and Down the Line, Cliff Warren, Raytek, Inc. (151)206

Platinum RTD Lithography, Haubold O. vom Berg, JUMO Process Control (156)80

Temperature Calibration Baths — State-of-the-Art, Ernie Pohl, Science / Electronics (154)265

Temperature Calibration Chamber, Brett Husselbaugh, TOBEK Computer Systems (154)160

Which Thermocouple is Best? The Commercial Realities in the 90s, Allan Paine, Leeds & Northrup (154)152

PROCESS CONTROL

DDC — Distributed Digital Control, Frank C. Pizzurro, Mobay Corporation (152)102

Expert Systems — Achieve Quality and Competitive Advantage, Joan B. Stoddard, Ph.D., Stoddard Productivity Systems (155)105

IR Non-contact Temperature Sensors Expand Up and Down the Line, Cliff Warren, Raytek, Inc. (151)206

Low-Power DC-Solenoid Valves, Donald Hoerr, Herion (154)142

Open-Architecture Process Control, William H. Moss, Computer Products Process Automation (155)98

PC and Operator Interface for the Hazardous or Dirty Environment, Dave Reynolds, Azonix (152)90

Plastic Control Valves, Bill Smith, Collins Instruments (152)100

The New Frontier — The Human Factor, Ernest Smith, Johnson Yokogawa Corp. (152)150

Windows for Data Acquisition and Control, Raymond Almgren, National Instruments (154) 234

FLOW / LEVEL

Flow Velocity Profiles, Thomas J. Scarpa, Edinboro Technologies (154)166

Magnetostrictive Tank Gauging, Wade D. Peterson, MTS Systems Corp. (153)108

Mass Flowmeters Measure Multiple Process Variables, Gary Bugher, Endress + Hauser (154)215

Regulators for Flow Control, John Cummings, W.A. Kates (151)102

Rotameter Correlation, Roger Gilmont (151)124

Technological Developments for Short-Range Level Measurement, Paul Shirley, Massa Products (152)131

Why Not Consider Using An Ultrasonic Flowmeter? Joseph Baumoel, Controlotron (155)189

GENERAL

Measurements & the Bureaucracy, Part 2, Milton H. Aronson (153)115

Science Fraud?, Milton H. Aronson (153)117

Why, On Earth, Would Environmental Scientists Cheat?, Gene Glassey, Fluid Data Systems (153)120

MISCELLANEOUS

Book News (151)133, (152)99, (153)93, (154)156, (155)110, (156)95

Calendar of Events (151)133, (152)99, (153)93, (154)156, (155)110, (156)95

Industry News (151)94, (152)69, (153)77, (154)138, (155)104, (156)85

Market Analysis (151)136, (152)8, (153)123, (154)175, (155)114, (156)106

Measurement & Control Data (151)113, (152)103, (153)101, (154)170, (155)111, (156)78